

Support Information

Assessment of the Sphericity Characteristics of Submicron Particles Using a Single-Particle Polar Nephelometer at an Urban Site in Japan

Maho Nakagawa^{1,2}, Tomoki Nakayama^{1,3*}, Hiroshi Sasago¹, Yuki Kuruma^{1,4}, Hikari Yai⁵, Shuhei Ogawa⁵, Yange Deng^{5,6}, Michihiro Mochida^{1,5}, and Yutaka Matsumi¹

¹*Institute for Space-Earth Environmental Research, Nagoya University, Furo-cho, Chikusa-ku, Nagoya, 464-8601, Japan.*

²*National Institute of Information and Communications Technology, 4-2-1 Nukui-kita, Koganei, Tokyo 184-8795, Japan*

³*Faculty of Environmental Science and Graduate School of Fisheries and Environmental Sciences, Nagasaki University, Bunkyo-machi, Nagasaki, 852-8521, Japan.*

⁴*National Institute of Advanced Industrial Science and Technology, Umezono, Tsukuba, 305-8560, Japan*

⁵*Graduate School of Environmental Studies, Nagoya University, Furo-cho, Chikusa-ku, Nagoya, 464-8601, Japan.*

⁶*National Institute for Environmental Studies, 16-2 Onogawa, Tsukuba, 305-8506, Japan.*

* Corresponding author. Tel: +81-95-819-2772, E-mail address: t-nakayama@nagasaki-u.ac.jp

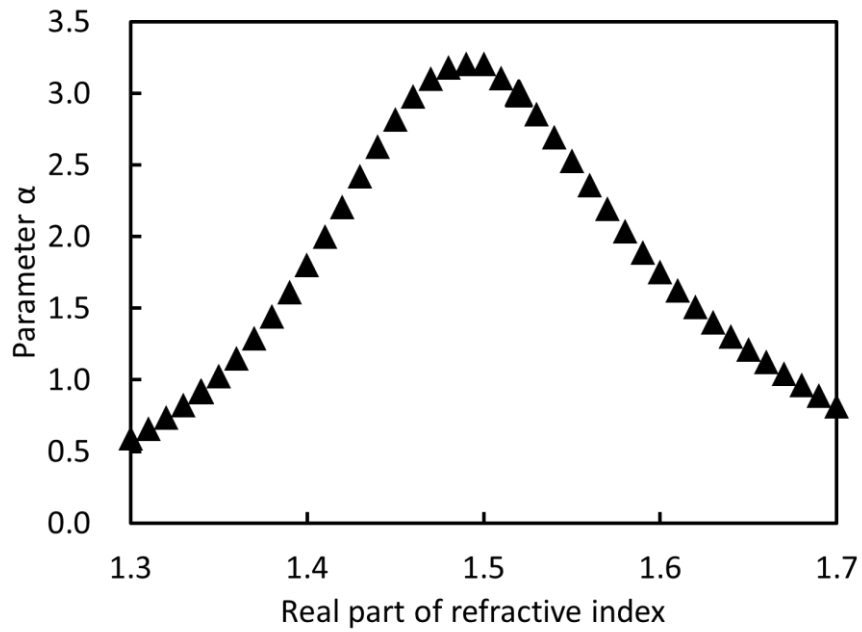


Fig. S1. Dependence of parameter α on the real part of complex refractive index at 532 nm, calculated on the basis of the Lorenz–Mie theory, assuming a homogeneous spherical particle with a diameter of 500 nm. The detection efficiency and angular resolution of each detector of the PN were taken into account in the calculation (Nakagawa et al., 2016).

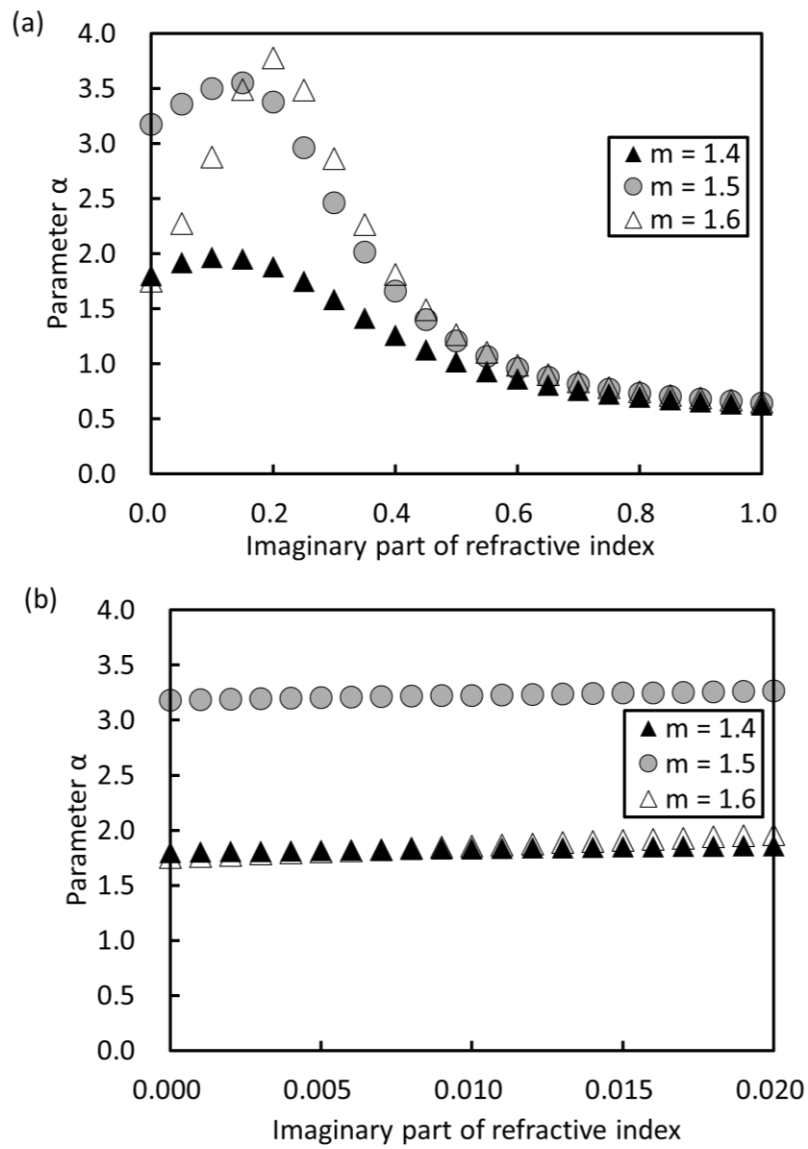


Fig. S2. Same as in Fig. S1 but for dependence of parameter α on the imaginary part of complex refractive index at 532 nm (a) from 0 to 1.0 and (b) from 0 to 0.020.

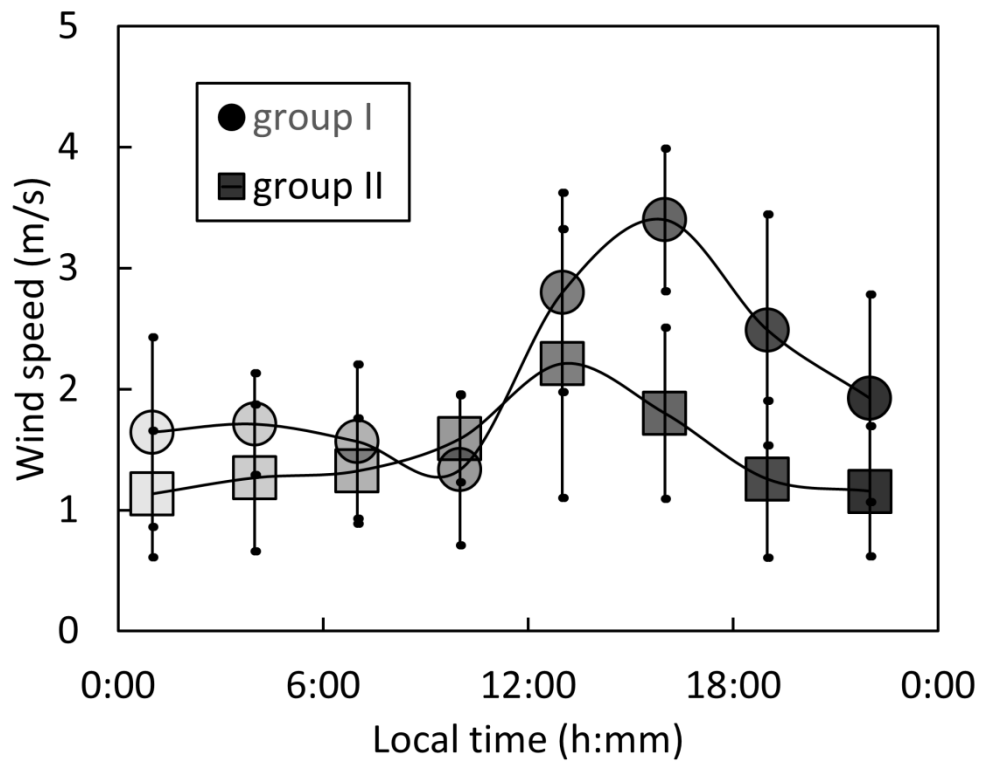


Fig. S3. Diurnal variations of wind speeds averaged over group I (2nd, 3rd, and 5th of July) (circles) and group II (4th, 6th, and 7th of July) (squares).

REFERENCE

Nakagawa, M., Nakayama, T., Sasago, H., Ueda, S., Venables, D. S., and Matsumi Y.

(2016). Design and characterization of a novel single-particle polar nephelometer,

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